

August 2015

## FCPF1300N80Z

# N-Channel SuperFET® II MOSFET

**800 V, 6 A, 1.3** Ω

#### **Features**

- $R_{DS(on)} = 1.05 \Omega (Typ.)$
- Ultra Low Gate Charge (Typ. Q<sub>q</sub> = 16.2 nC)
- Low E<sub>oss</sub> (Typ. 1.57 uJ @ 400V)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 48.7 pF)
- · 100% Avalanche Tested
- · RoHS Compliant
- · ESD Improved Capability

### **Applications**

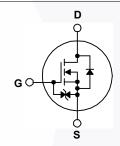
- · AC DC Power Supply
- · LED Lighting

### **Description**

SuperFET<sup>®</sup> II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. In addition, internal gate-source ESD diode allows to withstand over 2kV HBM surge stress. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as Audio, Laptop adapter, Lighting, ATX power and industrial power applications.







### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter			FCPF1300N80Z FCPF1300N80ZYD	Unit
V <sub>DSS</sub>	Drain to Source Voltage			800	V
V <sub>GSS</sub>	Cata to Source Voltage	- DC		±20	V
	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		6.0*	۸
ID	Drain Current	- Continuous (T <sub>C</sub> = 100°C)		3.8*	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	12*	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energ	у	(Note 2)	48	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	0.8	Α
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	0.26	mJ
ما الما	MOSFET dv/dt		100	1//	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		20	V/ns	
D	Dawer Dissipation	(T <sub>C</sub> = 25°C)		24	W
$P_{D}$	Power Dissipation  - Derate Above 25°C			0.19	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C
TL	Maximum Lead Temperature fo	r Soldering, 1/8" from Case for 5 S	econds	300	οС

#### \*Drain current limited by maximum junction temperature, with heatsink.

#### Thermal Characteristics

Symbol	Parameter	FCPF1300N80Z FCPF1300N80ZYD	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	5.2	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	*C/VV

Unit

## **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCPF1300N80Z	FCPF1300N80Z	TO-220F	Tube	N/A	N/A	50 units
FCPF1300N80ZYD	FCPF1300N80Z	TO-220F Y-formed	Tube	N/A	N/A	50 units

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Parameter

_						
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	800	-	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C	-	0.85	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_C = 125^{\circ}\text{C}$	-	-	25 250	μА
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±10	μΑ

Test Conditions

Min.

#### **On Characteristics**

Symbol

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 0.4$ mA	2.5	-	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}$	-	1.05	1.3	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 2 A	-	4.5	-	S

#### **Dynamic Characteristics**

-						
C <sub>iss</sub>	Input Capacitance	V 400 V V 0 V	-	661	880	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz	-	22.3	30	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 WH 12	-	0.74	-	pF
Coss	Output Capacitance	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	11.4	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 480 V, V <sub>GS</sub> = 0 V	-	48.7	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	$V_{DS} = 640 \text{ V}, I_D = 4 \text{ A},$	ı	16.2	21	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10 V	-	3.5	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4)	-	6.8	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	4	-	Ω

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		- /	14	38	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, I_D = 4 \text{ A},$	-	8.3	27	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_g$ = 4.7 $\Omega$	/-	33	76	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	6	22	ns

#### **Drain-Source Diode Characteristics**

$I_S$	Maximum Continuous Drain to Source Diode Forward Current		-	-	6	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	12	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 4 A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 4 A,	-	275	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	2.9	-	μС

#### Notes:

- 1. Repetitive rating: pulse width limited by maximum junction temperature.
- 2. I $_{AS}$  = 0.8 A, R $_{G}$  = 25  $\Omega$ , starting T $_{J}$  = 25°C
- 3. I\_{SD}  $\leq 6$  A, di/dt  $\leq 200$  A/µs, V\_DD  $\leq$  BV\_DSS, starting T\_J = 25°C
- 4. Essentially independent of operating temperature typical characteristic.

### **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

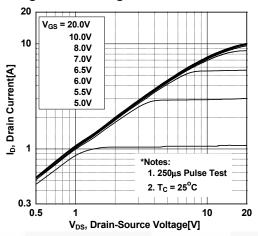


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

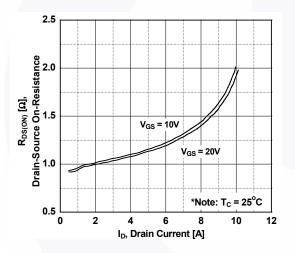


Figure 5. Capacitance Characteristics

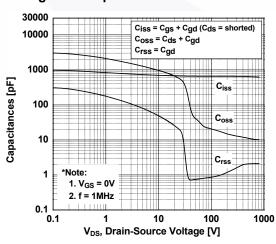


Figure 2. Transfer Characteristics

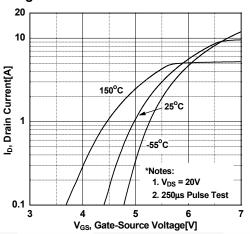


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

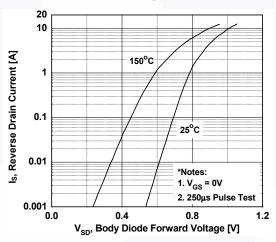
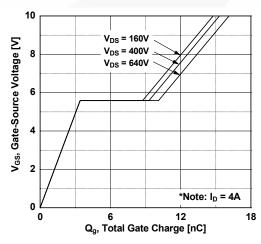


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

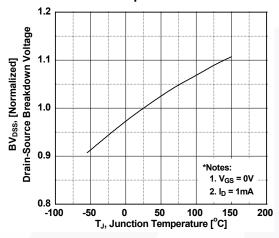


Figure 9. Maximum Safe Operating Area

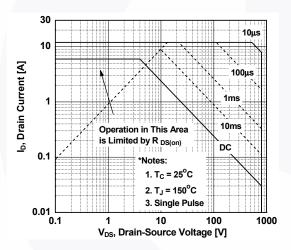


Figure 11. Eoss vs. Drain to Source Voltage

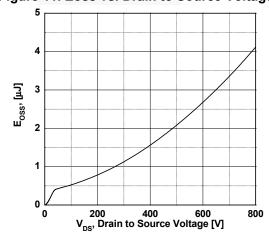


Figure 8. On-Resistance Variation vs. Temperature

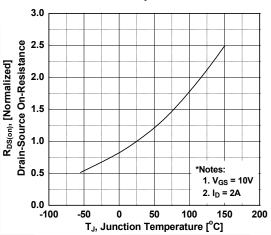
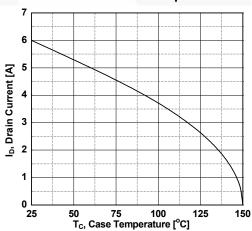
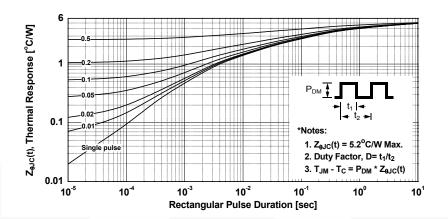


Figure 10. Maximum Drain Current vs. Case Temperature



## **Typical Performance Characteristics** (Continued)

Figure 12. Transient Thermal Response Curve



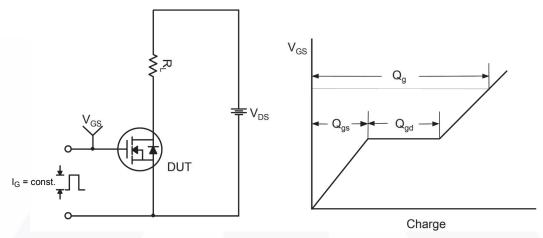


Figure 13. Gate Charge Test Circuit & Waveform

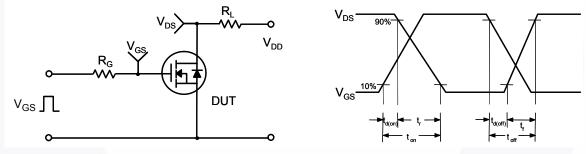


Figure 14. Resistive Switching Test Circuit & Waveforms



Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

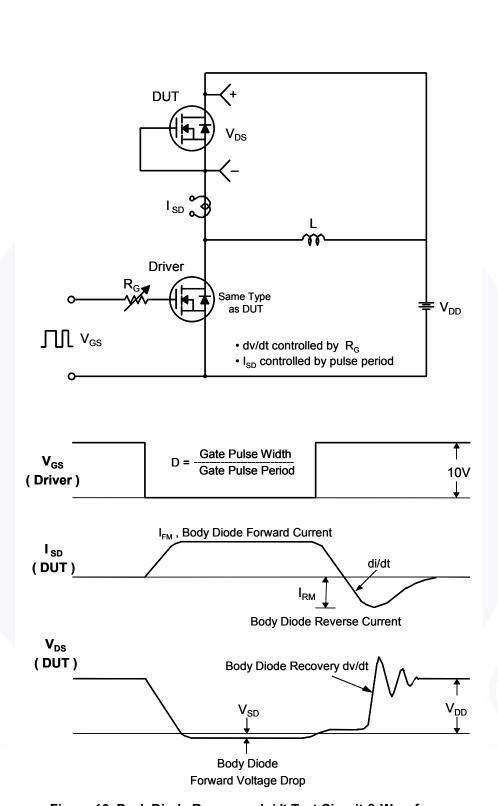
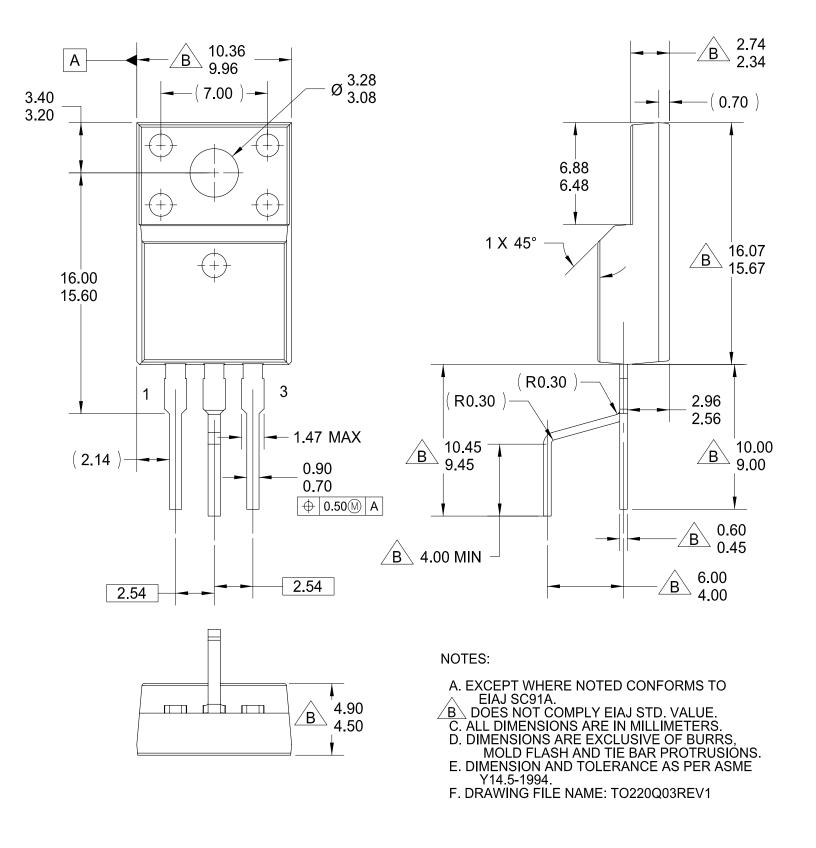
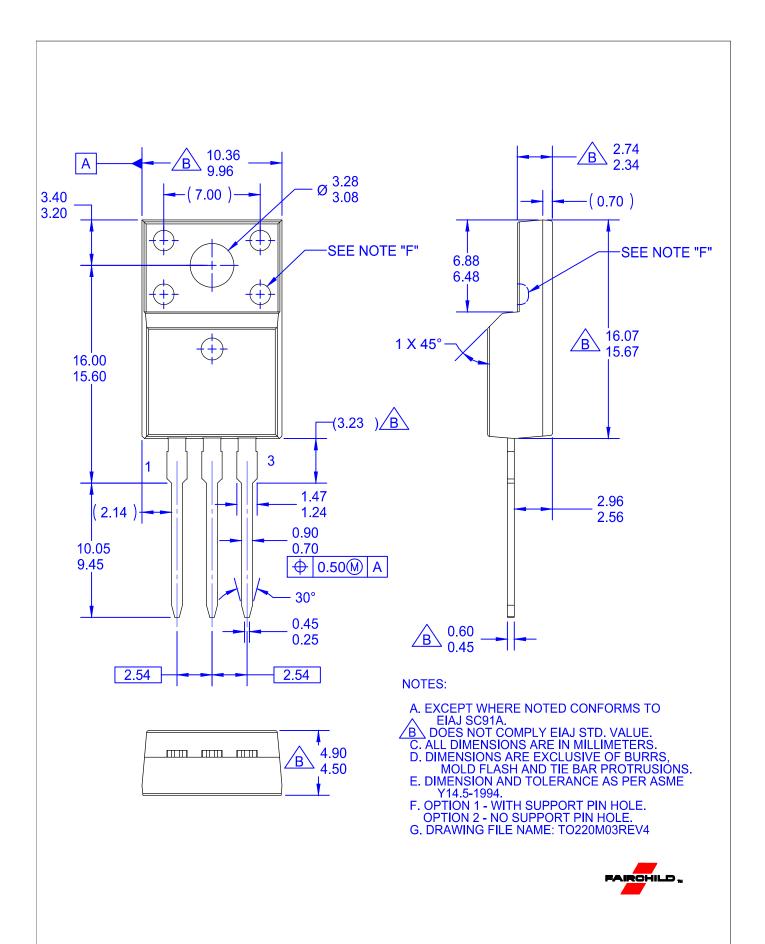


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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